



PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Haruo NISHIDA et al.

Group Art Unit: 2138

Application No.: 10/765,895

Examiner: C. BRITT

Filed: January 29, 2004

Docket No.: 118496

For: TEST CIRCUIT, INTEGRATED CIRCUIT, AND TEST METHOD

AMENDMENT UNDER 37 C.F.R. §1.111

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In reply to the March 23, 2007 Office Action, please consider the following:

Amendments to the Claims as reflected in the listing of claims;

Amendments to the Drawings include an attached replacement sheet; and

Remarks.